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4.5.2 Method 2: The Superimposition Method4.6 Validation and Performance of the 3D Measurement Methods; 4.6.1 Experiment with a Single Fiber; 4.6.2 3D Measurements of Micro-Fibers in Suspension; 4.7 Conclusion; References; 5 Other Applications; 5.1 Recording Plane Division Multiplexing (RDM) in Digital Holography for Resolution Enhancement; 5.1.1 Introduction of the Recording Plane Division Multiplexing Technique; 5.1.1.1 The SM Technique; 5.1.1.2 The ADM Technique; 5.1.1.3 The WDM Technique; 5.1.1.4 The PM Technique; 5.1.2 RDM Implemented in Pulsed Digital Holography for Ultra-Fast Recording
5.1.2.1 Introduction

Sommario/riassunto

Approaching the topic of digital holography from the practical perspective of industrial inspection, Digital Holography for MEMS and Microsystem Metrology describes the process of digital holography and its growing applications for MEMS characterization, residual stress measurement, design and evaluation, and device testing and inspection. Asundi also provides a thorough theoretical grounding that enables the reader to understand basic concepts and thus identify areas where this technique can be adopted. This combination of both practical and theoretical approach will ensure the